Search Notes			

Application/Control No.	Applicant(s)/Patent under Reexamination		
10/663,872	TEJIDOR ET AL.		
Examiner	Art Unit		
Jacob Cheu	1641		

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SEARCHED				
Class	Subclass	Date	Examiner	
436	69	6/1	1	
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INTERFERENCE SEARCHED				
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
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